

IPI80P04P4L-08, IPP80P04P4L-08

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics <sup>2)</sup>						
Thermal resistance, junction - case	$R_{\mathrm{thJC}}$	-	-	-	2.0	K/W

	uise					
Thermal resistance, junction - ambient, leaded	$R_{\mathrm{thJA}}$	-	-	-	62	
SMD version, device on PCB	$R_{\mathrm{thJA}}$	minimal footprint	-	-	62	
		6 cm <sup>2</sup> cooling area <sup>2)</sup>	-	-	40	

**Electrical characteristics,** at  $T_j$ =25 °C, unless otherwise specified

### Static characteristics

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, <i>I</i> <sub>D</sub> = -1mA	-40	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = -120 \mu A$	-1.2	-1.7	-2.2	
Zero gate voltage drain current	/ <sub>DSS</sub>	V <sub>DS</sub> =-32V, V <sub>GS</sub> =0V, 7 <sub>j</sub> =25°C	-	-0.05	-1	μΑ
		V <sub>DS</sub> =-32V, V <sub>GS</sub> =0V, T <sub>j</sub> =125°C <sup>2)</sup>	-	-20	-200	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =-16V, V <sub>DS</sub> =0V	-	-	-100	nA
Drain-source on-state resistance	$R_{\rm DS(on)}$	V <sub>GS</sub> =-4.5V, <i>I</i> <sub>D</sub> =-40A	-	9.9	13.3	mΩ
		V <sub>GS</sub> =-4.5V, / <sub>D</sub> =-40A, SMD version	-	9.6	13	
		V <sub>GS</sub> =-10V, / <sub>D</sub> =-80A	-	6.8	8.2	
		V <sub>GS</sub> =-10V, <i>I</i> <sub>D</sub> =-80A, SMD version	-	6.5	7.9	



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# Dynamic characteristics<sup>2)</sup>

Input capacitance	C <sub>iss</sub>		-	4177	5430	pF
Output capacitance	C <sub>oss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =-25V, <i>f</i> =1MHz	-	1185	1778	Ī
Reverse transfer capacitance	C <sub>rss</sub>		-	45	90	Ī
Turn-on delay time	t <sub>d(on)</sub>		-	12	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =-20V, V <sub>GS</sub> =-10V, / <sub>D</sub> =-80A, R <sub>G</sub> =3.5Ω	-	11	-	Ī
Turn-off delay time	$t_{d(off)}$		-	42	-	]
Fall time	t <sub>f</sub>		-	35	-	Ţ

# Gate Charge Characteristics<sup>2)</sup>

Gate to source charge	Q <sub>gs</sub>		-	14	18	nC
Gate to drain charge	Q <sub>gd</sub>	V <sub>DD</sub> =-32V, / <sub>D</sub> =-80A, V <sub>GS</sub> =0 to -10V	-	10	20	
Gate charge total	Qg	$V_{\rm GS}$ =0 to -10V	-	71	92	
Gate plateau voltage	V <sub>plateau</sub>		-	-3.7	-	V

### **Reverse Diode**

Diode continous forward current <sup>2)</sup>	I <sub>S</sub>	∙7 <sub>c</sub> =25°C	-	-	-80	А
Diode pulse current <sup>2)</sup>	I <sub>S,pulse</sub>	/ <sub>C</sub> -23 C	I	-	-320	
Diode forward voltage	$V_{\rm SD}$	V <sub>GS</sub> =0V, / <sub>F</sub> =-80A, 7 <sub>j</sub> =25°C	-	-1	-1.3	V
Reverse recovery time <sup>2)</sup>	t <sub>rr</sub>	V <sub>R</sub> =-20V, <i>I<sub>F</sub>=-</i> 50A, d <i>i<sub>F</sub></i> /d <i>t</i> =-100A/µs	-	46	-	ns
Reverse recovery charge <sup>2)</sup>	Q <sub>rr</sub>	d <i>i<sub>F</sub>/dt=</i> -100A/µs	-	43	-	nC

<sup>1)</sup> Defined by design. Not subject to production test.

 $^{2)}$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



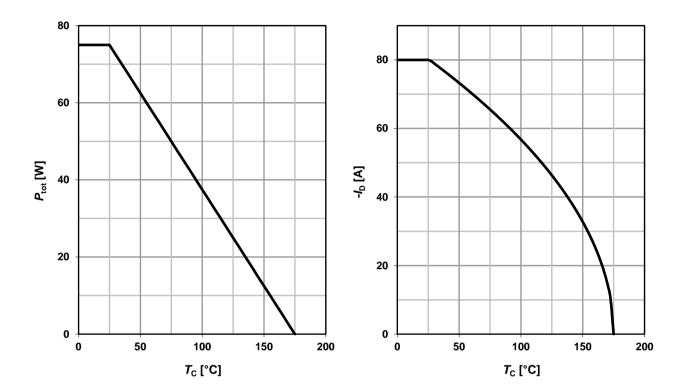
# IPI80P04P4L-08, IPP80P04P4L-08

# **1 Power dissipation**

 $P_{tot} = f(T_C); V_{GS} \le -6V$ 

2 Drain current

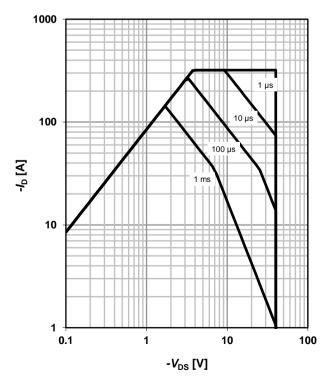
 $I_{\rm D} = f(T_{\rm C}); V_{\rm GS} \leq -6V; \text{SMD}$ 



#### 3 Safe operating area

$$I_{\rm D} = f(V_{\rm DS}); T_{\rm C} = 25 \,^{\circ}\text{C}; D = 0; \text{SMD}$$

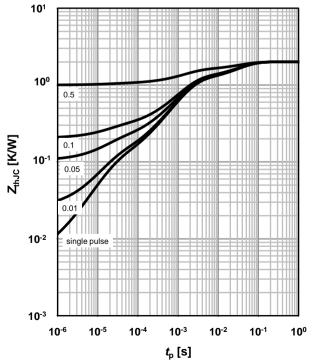
parameter: t<sub>p</sub>



# 4 Max. transient thermal impedance

 $Z_{\rm thJC} = f(t_{\rm p})$ 

parameter:  $D = t_p/T$ 





parameter: V<sub>GS</sub>

320

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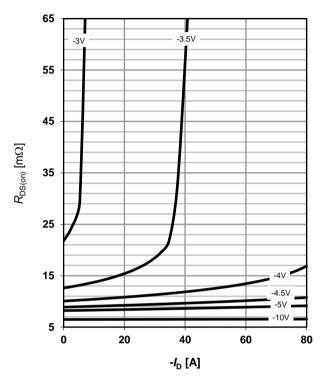
### IPI80P04P4L-08, IPP80P04P4L-08

# 5 Typ. output characteristics $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \,^{\circ}\text{C}; \, \text{SMD}$

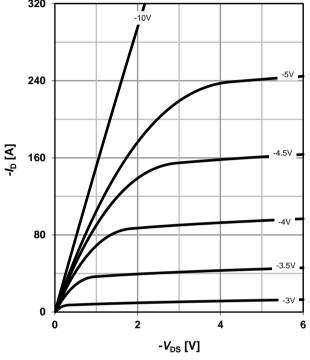
6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_i = 25 \text{ °C}; SMD$ 

parameter: V<sub>GS</sub>

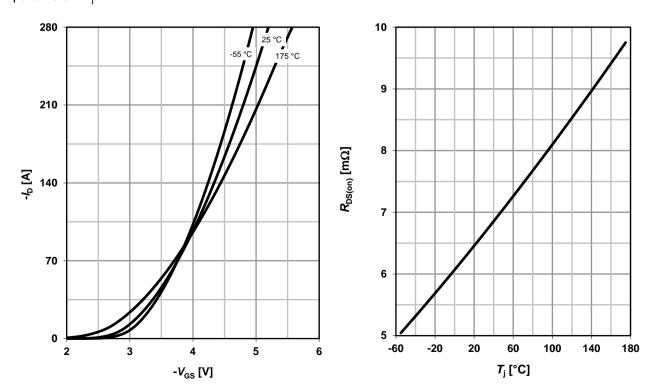


8 Typ. drain-source on-state resistance  $R_{DS(on)} = f(T_j); I_D = -80 \text{ A}; V_{GS} = -10 \text{ V}; \text{ SMD}$ 



### 7 Typ. transfer characteristics

 $I_{\rm D} = f(V_{\rm GS}); V_{\rm DS} = -6V$ parameter: T<sub>j</sub>







### IPI80P04P4L-08, IPP80P04P4L-08

# 9 Typ. gate threshold voltage

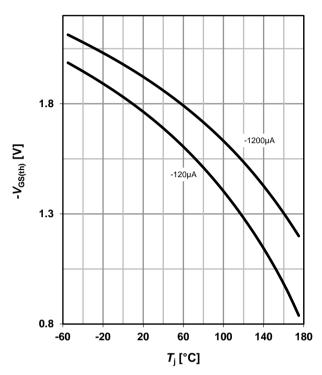
10 Typ. capacitances

10<sup>4</sup>

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 

 $V_{\rm GS(th)} = f(T_j); V_{\rm GS} = V_{\rm DS}$ 

parameter: I<sub>D</sub>

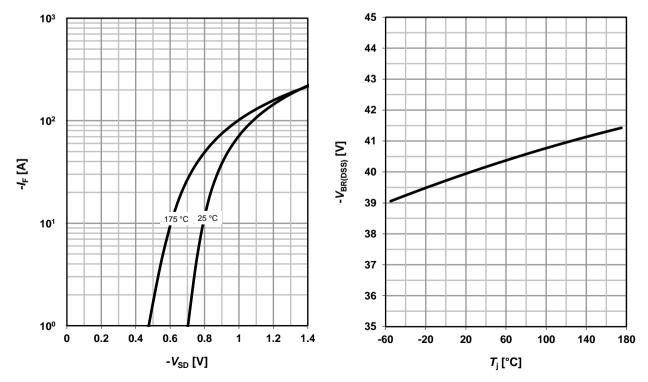


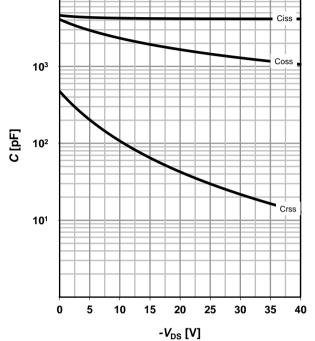
# 11 Typical forward diode characteristicis

 $I_F = f(V_{SD})$ 

12 Drain-source breakdown voltage  $V_{BR(DSS)} = f(T_j); I_D = -1 \text{ mA}$ 









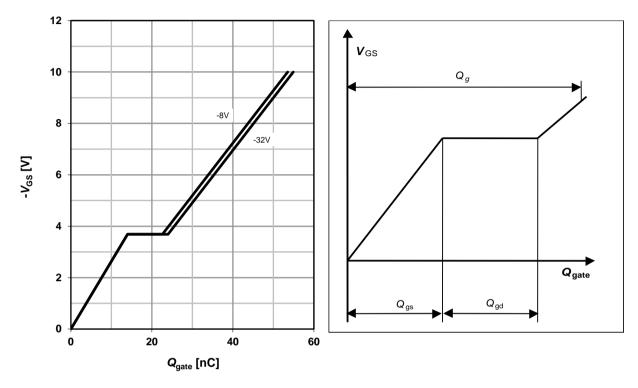
# IPI80P04P4L-08, IPP80P04P4L-08

# 13 Typ. gate charge

14 Gate charge waveforms

 $V_{GS} = f(Q_{gate}); I_D = -80 \text{ A pulsed}$ 

parameter:  $V_{\text{DD}}$ 





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# IPI80P04P4L-08, IPP80P04P4L-08

**Revision History** 

Version	Date	Changes
1.0	27.04.2011	Final Data Sheet
1.1	03.07.2019	V <sub>GS</sub> changed